

FORM PTO-1449 (Rev. 2-32)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. KIK01 P-322A	SERIAL NO. 10/737,336
O I P E J C 1 0 APR 05 2004 PATENT & TRADEMARK OFFICE		APPLICANTS Kenichiro Kobayashi et al.	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)		FILING DATE December 16, 2003	GROUP 2614 2863

## **U.S. PATENT DOCUMENTS**

## **FOREIGN PATENT DOCUMENTS**

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
X5	9 0 4 9 7 0 6	02/18/1997	Japan			X	
X5	7 1 1 0 2 1 6	04/24/1995	Japan			X	

**OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)**

**EXAMINER:** Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

(Form PTO-1449 [6-41])

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT			
(Use several sheets if necessary)			
		APPLICANT(S) Kenichiro Kobayashi et al.	
		FILING DATE	GROUP <i>2863</i>

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE
<i>X5</i>	5 3 4 3 2 8 7	08/30/1994	Wilkins			
<i>1</i>	4 6 2 1 0 6 3	11/04/1986	Wyatt et al.			
<i>1</i>	4 7 9 4 3 8 4	12/27/1988	Jackson			
<i>X5</i>	5 6 3 3 7 1 4	05/27/1997	Nyyssonen			

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	Y	N
<i>X5</i>	DE 19 7 3 9 6 79 A1 10/1998	Germany						
<i>1</i>	2 7 0 1 7 6 2 08/1994	France						
	DE 19 8 1 7 6 64 A1 11/1999	Germany						
	DE 19 9 0 9 2 35 A1 09/1999	Germany						
<i>X5</i>	DE 19 6 2 0 4 19 A1 11/1997	Germany						

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER INITIAL	
<i>X5</i>	U.S. Patent Application Publication 2002/0080264, publication date June 27, 2002 entitled METHOD AND APPARATUS FOR DIRECT IMAGE PICK-UP OF GRANULAR SPECK PATTERN GENERATED BY REFLECTING LIGHT OF LASER BEAM

EXAMINER	<i>Ming S</i>	DATE CONSIDERED	<i>09/27/04</i>
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